The RF Sub-Micron MOSFET Line RF Power Field Effect Transistors | MRF5S19150R3 N-Channel Enhancement-Mode Lateral MOSFETs MRF5S19150SR3

Designed for PCN and PCS base station applications at frequencies from 1.9 to 2.0 GHz. Suitable for TDMA, CDMA and multicarrier amplifier applications.

Typical 2-Carrier N-CDMA Performance for V_{DD} = 28 Volts, $P_{out} = 32 \text{ Watts}, I_{DQ} = 1400 \text{ mA}, f1 = 1958.75 \text{ MHz}, f2 = 1961.25 \text{ MHz}$ IS-95 CDMA (Pilot, Sync, Paging, Traffic Codes 8 Through 13) 1.2288 MHz Channel Bandwidth Carrier. Adjacent Channels Measured over a 30 kHz Bandwidth at f1 -885 kHz and f2 +885 kHz. Distortion Products Measured over 1.2288 MHz Bandwidth at f1 -2.5 MHz and f2 +2.5 MHz. Peak/Avg. = 9.8 dB @ 0.01% Probability on CCDF.

Output Power — 32 Watts Avg.

Power Gain — 14 dB

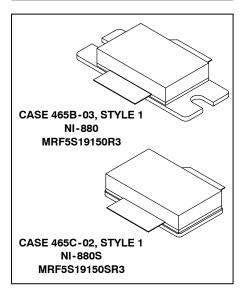
Efficiency - 26%

ACPR — -50 dB

IM3 - -36.5 dBc

- Internally Matched, Controlled Q, for Ease of Use
- High Gain, High Efficiency and High Linearity
- Integrated ESD Protection
- Designed for Maximum Gain and Insertion Phase Flatness
- Capable of Handling 5:1 VSWR, @ 28 Vdc, f1 = 1960 MHz, 100 Watts CW Output Power
- **Excellent Thermal Stability**
- Qualified Up to a Maximum of 32 V Operation
- In Tape and Reel. R3 Suffix = 250 Units per 56 mm, 13 inch Reel.

1990 MHz, 32 W, 28 V LATERAL N-CHANNEL **RF POWER MOSFETs**



MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	65	Vdc
Gate - Source Voltage	V _{GS}	-0.5, +15	Vdc
Total Device Dissipation @ T _C = 25°C Derate above 25°C	P _D	357 2	Watts W/°C
Storage Temperature Range	T _{stg}	- 65 to +150	°C
Operating Junction Temperature	TJ	200	°C
CW Operation	CW	100	Watts

THERMAL CHARACTERISTICS

Characteristic	Symbol	Value (1,2)	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$		°C/W
Case Temperature 80°C, 100 W CW		0.49	
Case Temperature 80°C, 32 W CW		0.53	

- (1) MTTF calculator available at http://www.motorola.com/semiconductors/rf. Select Tools/Software/Application Software/Calculators to access the MTTF calculators by product.
- (2) Refer to AN1955/D, Thermal Measurement Methodology of RF Power Amplifiers. Go to http://www.motorola.com/semiconductors/rf. Select Documentation/Application Notes - AN1955.

NOTE - CAUTION - MOS devices are susceptible to damage from electrostatic charge. Reasonable precautions in handling and packaging MOS devices should be observed.





ESD PROTECTION CHARACTERISTICS

Test Conditions	Class
Human Body Model	1 (Minimum)
Machine Model	M3 (Minimum)
Charge Device Model	C7 (Minimum)

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					
Zero Gate Voltage Drain Leakage Current (V _{DS} = 65 Vdc, V _{GS} = 0 Vdc)	I _{DSS}		_	10	μAdc
Zero Gate Voltage Drain Leakage Current (V _{DS} = 28 Vdc, V _{GS} = 0 Vdc)	I _{DSS}	_	_	1	μAdc
Gate-Source Leakage Current (V _{GS} = 5 Vdc, V _{DS} = 0 Vdc)	I _{GSS}	_		1	μAdc
ON CHARACTERISTICS	•	•		•	•
Gate Threshold Voltage ($V_{DS} = 10$ Vdc, $I_D = 360 \mu Adc$)	V _{GS(th)}	2.5	2.8	3.5	Vdc
Gate Quiescent Voltage (V _{DS} = 28 Vdc, I _D = 1400 mAdc)	V _{GS(Q)}	_	3.8	_	Vdc
Drain-Source On-Voltage (V _{GS} = 10 Vdc, I _D = 3.6 Adc)	V _{DS(on)}	_	0.24	_	Vdc

DYNAMIC CHARACTERISTICS

 $(V_{DS} = 10 \text{ Vdc}, I_{D} = 3.6 \text{ Adc})$

Forward Transconductance

Reverse Transfer Capacitance (1) $(V_{DS} = 28 \text{ Vdc}, V_{GS} = 0, f = 1 \text{ MHz})$	C _{rss}	_	3.1	_	pF

FUNCTIONAL TESTS (In Motorola Test Fixture, 50 ohm system) 2-Carrier N-CDMA, 1.2288 MHz Channel Bandwidth Carriers. Peak/Avg = 9.8 dB @ 0.01% Probability on CCDF.

Common-Source Amplifier Power Gain (V_{DD} = 28 Vdc, P_{out} = 32 W Avg, I_{DQ} = 1400 mA, f1 = 1930 MHz, f2 = 1932.5 MHz and f1 = 1987.5 MHz, f2 = 1990 MHz)	G _{ps}	13	14	_	dB
Drain Efficiency $(V_{DD} = 28 \text{ Vdc}, P_{out} = 32 \text{ W Avg}, I_{DQ} = 1400 \text{ mA}, f1 = 1930 \text{ MHz}, f2 = 1932.5 \text{ MHz} and f1 = 1987.5 \text{ MHz}, f2 = 1990 \text{ MHz})$	η	24	26	_	%
Third Order Intermodulation Distortion ($V_{DD}=28~Vdc,~P_{out}=32~W~Avg,~I_{DQ}=1400~mA,~f1=1930~MHz,~f2=1932.5~MHz~and~f1=1987.5~MHz,~f2=1990~MHz;~IM3~measured~over~1.2288~MHz~Bandwidth~at~f1~-2.5~MHz~and~f2~+2.5~MHz~referenced~to~carrier~channel~power.)$	IM3	_	-36.5	-35	dBc
Adjacent Channel Power Ratio $ \text{(V}_{DD} = 28 \text{ Vdc, P}_{out} = 32 \text{ W Avg, I}_{DQ} = 1400 \text{ mA, f1} = 1930 \text{ MHz,} \\ \text{f2} = 1932.5 \text{ MHz and f1} = 1987.5 \text{ MHz, f2} = 1990 \text{ MHz; ACPR} \\ \text{measured over 30 kHz Bandwidth at f1} -885 \text{ MHz and f2} +885 \text{ MHz)} $	ACPR	_	-50	-48	dBc
Input Return Loss (V _{DD} = 28 Vdc, P _{out} = 32 W Avg, I _{DQ} = 1400 mA, f1 = 1930 MHz, f2 = 1932.5 MHz and f1 = 1987.5 MHz, f2 = 1990 MHz)	IRL	_	-17	-9	dB

⁽¹⁾ Part is internally matched both on input and output.

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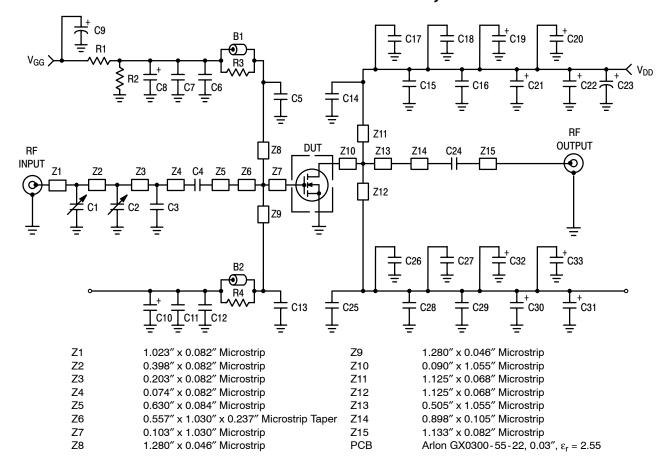


Figure 1. MRF5S19150 Test Circuit Schematic

Table 1. MRF5S19150 Test Circuit Component Designations and Values

Part	Description
B1, B2	Short RF Beads
C1, C2	0.6 – 4.5 Variable Capacitors, Gigatrim
C3	0.8 pF Chip Capacitor, B Case
C4, C5, C13, C14, C24, C25	9.1 pF Chip Capacitors, B Case
C8, C10	1.0 μF, 50 V SMT Tantalum Capacitors
C6, C12, C16, C17, C18, C27, C28, C29	0.1 μF Chip Capacitors, B Case
C7, C11, C15, C26	1000 pF Chip Capacitors, B Case
C9	100 μF, 50 V Electrolytic Capacitor
C23	470 μF, 63 V Electrolytic Capacitor
C19, C20, C21, C22, C30, C31, C32, C33	22 μF, 35 V Tantalum Capacitors
R1	1 kΩ Chip Resistor
R2	560 kΩ Chip Resistor
R3, R4	12 Ω Chip Resistors

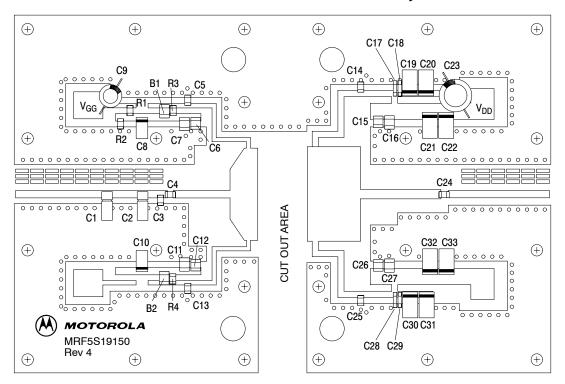


Figure 2. MRF5S19150 Test Circuit Component Layout

TYPICAL CHARACTERISTICS

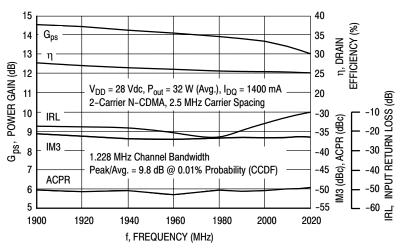


Figure 3. 2-Carrier N-CDMA Broadband Performance

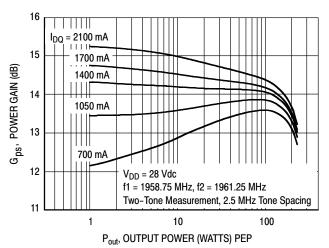
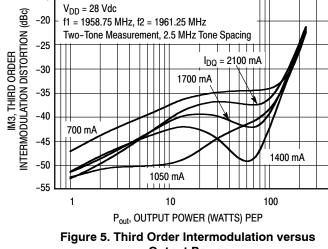


Figure 4. Two-Tone Power Gain versus **Output Power**



Output Power

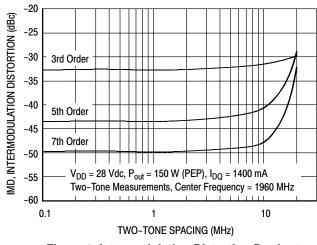


Figure 6. Intermodulation Distortion Products versus Tone Spacing

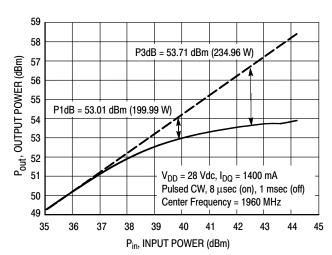


Figure 7. Pulse CW Output Power versus **Input Power**

TYPICAL CHARACTERISTICS

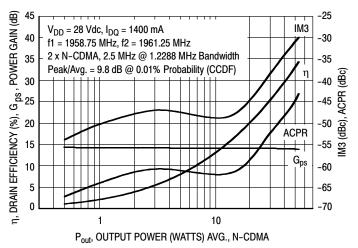


Figure 8. 2-Carrier N-CDMA ACPR, IM3, Power Gain, Drain Efficiency versus Output Power

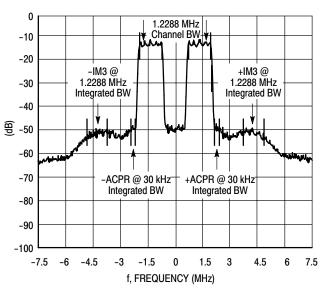
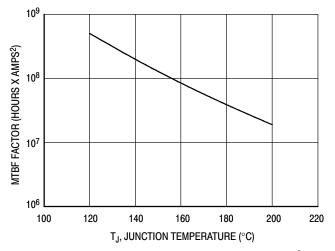
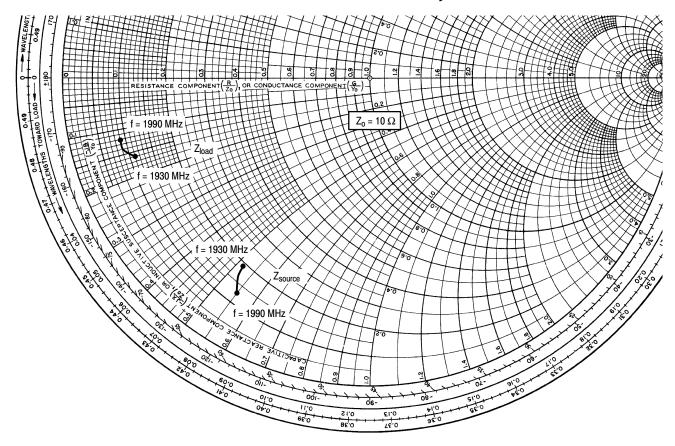


Figure 9. 2-Carrier N-CDMA Spectrum



This above graph displays calculated MTBF in hours x ampere² drain current. Life tests at elevated temperatures have correlated to better than $\pm 10\%$ of the theoretical prediction for metal failure. Divide MTBF factor by I_D² for MTBF in a particular application.

Figure 10. MTBF Factor versus Junction Temperature



 V_{DD} = 28 V, I_{DQ} = 1400 mA, P_{out} = 32 W Avg.

f MHz	$\mathbf{Z_{source}}_{\Omega}$	$\mathbf{Z_{load}}_{\Omega}$
1930	1.89 - j5.24	1.06 - j1.58
1960	1.64 - j5.29	0.88 - j1.37
1990	1.3 - j5.49	0.90 - j1.21

 Z_{source} = Test circuit impedance as measured from gate to ground.

Z_{load} = Test circuit impedance as measured from drain to ground.

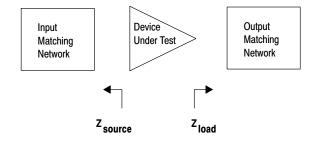
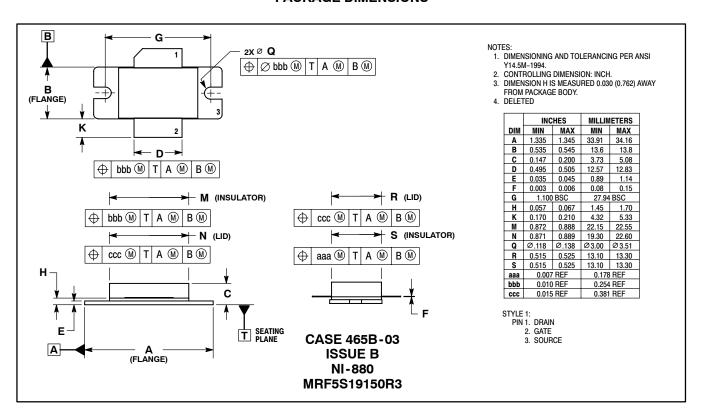
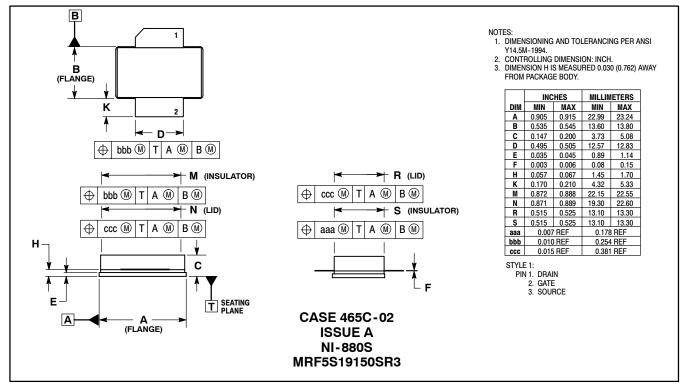


Figure 11. Series Equivalent Input and Output Impedance

PACKAGE DIMENSIONS





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